

UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	. FILING DATE		FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/894,334	06/27/2001		Qing Ma	42390P10606	6477
8791	7590	09/15/2004		EXAM	INER
	SOKOLOF	COLEMAN,	COLEMAN, WILLIAM D		
SEVENTH		ART UNIT	PAPER NUMBER		
LOS ANGE	LOS ANGELES, CA 90025-1030 2823				

DATE MAILED: 09/15/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	
			UN.
Office Action Summary	09/894,334	MA ET AL.	
cso / loud!! Guillinuity	Examiner	Art Unit	
The MAILING DATE of this communica	W. David Coleman	2823	ddross
Period for Reply	ation appears on the cover sneet w	un the correspondence at	aaress
A SHORTENED STATUTORY PERIOD FOR THE MAILING DATE OF THIS COMMUNICATE OF THIS COMMUNICATE SIX (6) MONTHS from the mailing date of this communication of the period for reply specified above is less than thirty (30) of the specified of the maximum statuton of the specified above, the maximum statuton of the specified above the specified above the maximum statuton of the specified above the specified above the maximum statuton of the specified above.	ATION. 37 CFR 1.136(a). In no event, however, may a rication. days, a reply within the statutory minimum of thir ory period will apply and will expire SIX (6) MON I, by statute, cause the application to become AE	eply be timely filed ty (30) days will be considered time ITHS from the mailing date of this BANDONED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed	on 13 <i>April 2004</i>		
) This action is non-final.		
3) Since this application is in condition for		ers, prosecution as to th	e merits is
closed in accordance with the practice	•	•	
Disposition of Claims			
4)	withdrawn from consideration.		
Application Papers			
9) The specification is objected to by the E			
10) The drawing(s) filed on is/are: a			
Applicant may not request that any objection			
Replacement drawing sheet(s) including the 11) The oath or declaration is objected to be	•		
Priority under 35 U.S.C. § 119			
•	ocuments have been received. ocuments have been received in A the priority documents have been al Bureau (PCT Rule 17.2(a)).	Application No received in this Nationa	ıl Stage
Attachment(s)			
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-892) 	•	Summary (PTO-413) s)/Mail Date	
2) Notice of Draftsperson's Patent Drawing Review (PTC 3) Information Disclosure Statement(s) (PTO-1449 or PT Paper No(s)/Mail Date	· · · · · · · · · · · · · · · · · ·	nformal Patent Application (PI	ΓΟ-152)

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 1, 3, 4, 5, 7, 8, 9,10, 11 and 12 are rejected under 35 U.S.C. 102(e) as being anticipated by Howe et al., U.S. Patent 6,210,988 B1.
- 3. See **FIGS. 1-16** where <u>Howe</u> discloses a method of manufacturing a semiconductor.
- 4. Pertaining to claim 1, <u>Howe</u> discloses a method comprising:

over an area of a substrate 10, forming a plurality of three dimensional first structures(MOSFETs);

following forming the first structures, conformally introducing a sacrificial material (SiO2) over the area of the substrate including on a top portion and a side portion of the plurality of first structures;

introducing a second structural material (polysilicon-germanium) over the sacrificial material;

exposing a portion of the sacrificial material (as seen in **FIG. 4 & 5** also see column 7, lines 9-14);

removing the sacrificial material; and

Application/Control Number: 09/894,334 Page 3

Art Unit: 2823

wherein removing the sacrificial material comprises suspending the second structural material as a second structure electrically coupled to the first structure (see FIG. 7).

- 5. Pertaining to claim 3, <u>Howe</u> discloses the method of claim 1, wherein exposing a portion of the sacrificial material comprises removing a portion of the second structural material. comprises removing a portion of the second structural material.
- 6. Pertaining to claim 4, <u>Howe</u> discloses the method of claim 1, prior to introducing the second structural material, further comprising patterning the sacrificial material (Howe utilizes patterning to remove a portion to expose a source/drain electrode).
- 7. Pertaining to claim 5, <u>Howe</u> discloses the method of claim 1, wherein the first structural material comprises silicon and the sacrificial material comprises silicon dioxide and introducing the sacrificial material comprises growing.
- 8. Pertaining to claim 7, <u>Howe</u> discloses the method of claim 1, wherein patterning the first structures defines a plurality of first areas of the portion of the substrate occupied by the first structures and at least a second area of the portion of the substrate free of the first structures, and introducing the sacrificial material comprises introducing the sacrificial material at least over the second area.
- 9. Pertaining to claim 8, <u>Howe</u> teaches a method comprising:

Art Unit: 2823

over an area of a surface of a substrate 110, lithographically patterning a plurality of first structures, the plurality of first structures having a first dimension about the surface of the substrate and a second different dimension;

following forming the plurality of first structures, conformally introducing a sacrificial material layer over the area of the substrate including on a portion of the plurality of first structures;

patterning the sacrificial material;

forming second structures over the sacrificial material;

removing the sacrificial material; and

wherein removing the sacrificial material comprises suspending the second structure by the first structure, and wherein the second structure is electrically coupled to the first structure.

- 10. Pertaining to claim 10, <u>Howe</u> teaches the method of claim 8, prior to removing the sacrificial material, further comprising exposing a portion of the sacrificial material.
- 11. Pertaining to claim 11, <u>Howe</u> teaches the method of claim 10, wherein exposing a portion of the sacrificial material comprises removing a portion of the second structural material.
- 12. Pertaining to claim 12, <u>Howe</u> teaches the method of claim 8, wherein the sacrificial material comprises silicon dioxide and introducing the sacrificial material comprises growing.

Application/Control Number: 09/894,334 Page 5

Art Unit: 2823

Conclusion

13. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

- 14. A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.
- 15. Any inquiry concerning this communication or earlier communications from the examiner should be directed to W. David Coleman whose telephone number is 571-272-1856. The examiner can normally be reached on 9:00 AM-5:00 PM.
- 16. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri can be reached on 571-272-1855. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Application/Control Number: 09/894,334

Art Unit: 2823

Information regarding the status of an application may be obtained from the Patent 17.

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

W. David Coleman **Primary Examiner** Art Unit 2823

Page 6

WDC